



Mechanical Data	Notes
Dice size	Ax:330um,Ay:330um,Bx:150um,By:150um
Wafer size	6"(good die:139,000pcs)
Chip Thickness	165um(max)
Scribe line width	50um
Top metal	Ti-Ni-Ag
Back side metal	Ti-Ni-Ag for soldering

Parameter	Symbol	Conditions	Value	Unit
Reverse stand-off voltage	VRWM		5	V
Peak pulse power	PPP	tp=8/20us	75	W
Peak pulse current	IPP	tp=8/20us	5	A
Electrostatic discharge	VESD	IEC61000-4-2	± 25(AIR)	KV
Max.junction temp.	Tj		+150	°C

Characteristics TA=25°C

Parameter	Symbol	Condition	Min.	Typ.	Max.	Unit
Breakdown Voltage	VBR	IT=1mA	6.1		8.5	V
Reverse leakage current	IR	VR=5V			0.03	uA
Clamping voltage	VC	IPP=1A IPP=5A			9.0 15.0	V
Diode capacitance pin1 to 2	Cj	VR=0V f=1MHz	8.0	10.0	13.0	pf

Notes:

- (1)sampling testing:no bad dice inking/guaranteed good die >93%
- (2)Testing follow customer
- (3) $T_j = T_a + R_{th(j-a)} * (P_f + P_r)$, where $R_{th(j-a)}$ -thermal resistance, P_f -forward power dissipation, P_r -revers power dissipation
- (4)**For device testing